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~	AA	3,299,424	1/67	Vinding		)							
~	AB	3,852,755	12/74	Works et al.		١	1						
~	AC	4.075,632	2/21/78	Baldwin et al.		/	-						
$\sim$	AD	4,572,976	2/25/86	Fockens		\	_						
~	AE	4,656,463	4/7/87	Anders et al.		1	)						
<u>۸</u>	AF	4,700,179	10/87	Fancher		1							
a	AG	4,724,427	2/9/88	Carroll		1							
n	AH	4,743,864	5/88	Nakagawa et al.		1	(						
1	AI	4,800,543	1/89	Lyndon-James et al.		1	)	·					
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	AR	"Micron Morning	Report*, The	Idaho Statesman, July 16, 1993.			-						
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	AS	*A Low-Power Sp	read Spectrum	CMOS RFIC for Radio Identifica	tion Applications", by	John R. Tu	ttle, Conferen	ice					
V		Proceedings from	m RF Expo W	est, pp. 216-222, March 22-24, 199	94, San Jose, CA.		<del></del>	<u></u>					
	АТ	Provisional Applic	Provisional Application, Serial No. 60/023,321, Filed July 30, 1996.										
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N	АА	4,816	i,839	3/89	Landt			(		
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~	AC	4,853	3,705	8/89	Landt		_	_		
~	AD	4,854	-,328	8/8/89	Poliack		_			
n	AE	4,857	7,893	8/15/89	Carroll		/	_		
N	AF	4,862	L,160	8/29/89	Ekchian et al.					
v	AG	4,870	),419	9/26/89	Baldwin et al.		_			
~	AH	4,888	3,591	12/19/89	Landt et al.					
w	AI	4,890	1,072	12/26/89	Espe et al.			~		-
N	ΑJ	4,912	1,471	3/27/90	Tyburski et al.	···				
✓	AK	4,926	5,182	5/15/90	Ohta et al.					
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~	AR		*CMOS Analog In	tegrated Circu	nits Based on Weak Inversion Oper	ation*, by Eric Vittoz	and Jean F	ellrath, IEI	E Journal of	
			Solid State Circu	iits, Vol. SC-	12, No. 3, June 1977					
~	AS		Mitsubishi Motors	Corporation '	Web Page, 1995					
.00	АТ		*Digital RF/ID En	hances GPS",	by John R. Tuttle, Proceedings of	the Second Annual \	Wireless Sym	posium, pp.	406-411,	
"			February 15-18,	1994, Santa (	Clara, CA					

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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W	AA	5,030,807	7/91	Landt et al.			_	Ī		
~	AB	5,075,691	12/91	Garay et al.		_	-			
n	AC	5,081,458	1/92	Meunier		-	١			
a	AD	5,086,389	2/4/92	Hassett et al.		-	۱			
1	AE	5,122,687	6/92	Schmidt		_	<u>ر</u>			
~	AF	5,128,938	7/92	Borras		-	7		•	
1	AG	5,130,668	7/92	Emslie et al.		-	/			
1	АН	5,134,085 -	7/28/92	Gilgen et al.		_				
~	Al	5,142,292	8/92	Chang		_	/			
1	AJ	5,144,314	9/1/92	Malmberg et al.		-				
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N	AA	5,153,583	10/92	Murdoch		( <u>k</u>			
-	AB	5,164,985	11/17/92	Nysen et al.			)		
~	AC	5,175,774	12/29/92	Truax et al.		_			
1	AD	5,206,609	4/27/93	Mijuskovic		_			
N	AE	5,218,343	6/8/93	Stobbe et al.			_		
n	AF	5,231,273	7/93	Caswel			_		
5	AG	5,252,979	10/12/93	Nysen		_	_		
n	АН	5,272,367	12/21/93	Dennison et al.					
2	Al	5,287,112	2/15/94	Schuermann		_	_		
	ΑJ	5,294,928	3/15/94	Cooper et al.			~		
~	AK	5,300,875	4/5/89	Tuttle		_			
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~	AB	5,323	3,150	6/21/94	Tuttle			7	_	-	· · · · · ·	
تربرنا	AC	5,355	5,513	10/94	Clarke et a	al.		ノ	_	-		
v	AD	5,365	5,551	11/15/94	Snodgrass (	et al.		ر ا	_	-		
n	AE	5,374	1,930	12/20/94	Schuermani	1			_	~		
· -	AF	5,394	1,444	2/95	Silvey et al	l.			_	-		
01	AG	5,400	5,263	4/11/95	Tuttle			/	_		.*	
$\mathcal{N}$	AH	5,412	2,351	5/95	Nystrom et	al.		~	_	_	·	
i v	. AI	5,420	),757	5/30/95	Eberhardt -	et al.		_	_	-		
u	. AJ	5,430	0,441	7/95	Bickley et	al.		_	_			
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~	AB	5,541	,583	7/96	Mandelbaum				)				
w	AC	5,541	,585	7/96	Duhame et al.								
~	– AD	5,568	,512	10/96	Rotzoll								
N	AE	5,606	,323	2/97	Heinrich et al.				)				
a	AF	5,621	,412	4/15/97	Sharpe et al.			-					
N	AG	5,623	,224	4/22/97	Yamada et al.			_	)				
n	AH	5,649	,296	7/15/97	MacLellan et al.			_	_				
2	Al	5,657	,359	8/97	Sakae et al.	İ		_	_				
	AJ	5,677	,667	10/14/97	Lesesky et al.			_	7				
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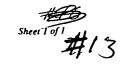
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